



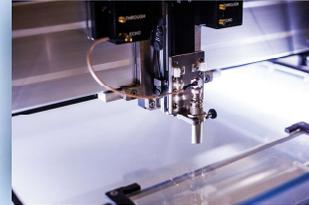
VUE 400-P

SCANNING ACOUSTIC MICROSCOPE

Semiconductor Package Failure Analysis
voids · disbonds · cracks · delamination · internal defects

Included Software Modes:

- Basic (user friendly)
- Advanced (detailed analysis)
- Production (automated scanning)
- Offline Analysis (virtual scanning)



info@okos.com

Customer Interface

Dual 22" HD LED Monitors

Fixtures

Tray Fixture
Optional Through
Transmission Bracket
LED illumination

Instrumentation

Digital Pulsar Receiver
Optional second channel
Up to 12 GHz Digitizer

Scan Area

Dual JEDEC Trays

Maintenance Free Scan Axis

Motor: Quad Linear Servo
Max Velocity: 1500 mm/s
Accuracy & Repeatability: +/- 0.5 micron

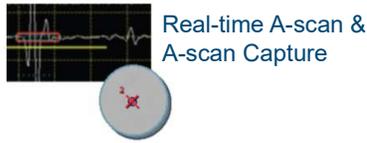
Scan Envelope: 380 mm

Low Maintenance Step Axis:
Step Envelope 350 mm

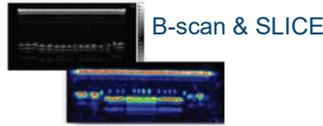
Low Maintenance Focus Axis:
Focus Envelope 50 mm

Dimensions:
0.9 m x 0.86 m x 1.18 m (WDH)
227 kg





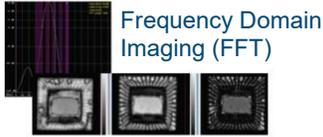
Real-time A-scan & A-scan Capture



B-scan & SLICE



Threshold Mapping (post processing)



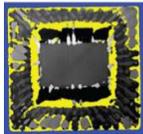
Frequency Domain Imaging (FFT)



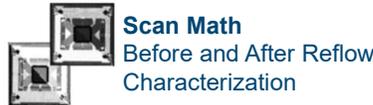
C-scan with Multi-gate SALI & SALI Groups



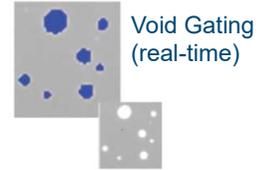
Cluster Analysis (post processing)



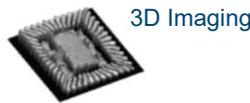
Advanced Time-of-Flight & Thickness Measurements



Scan Math Before and After Reflow Characterization



Void Gating (real-time)



3D Imaging

OKOS Digital Imaging System (ODIS)



VUE 400-P imaging power surpasses modern standards delivering premium FA Lab features to semiconductor fabrication facilities. ODIS is the latest Acoustic Microscopy software with rich technical content built on current platforms and industry feedback. It includes both time domain and frequency domain imaging in real-time. Advanced analysis is provided through quantitative tools for measurement and classification of parts.

The Analysis version of ODIS allows non-scanning computers to virtually scan, view, and analyze data for simultaneous real-time analysis or post collection review. Previously undetected flaws can now be imaged with poled peak analysis. Supplied with your choice of Windows 7 or 10.

- Counterfeit Detection
- Product Inspection
- Product Reliability
- Quality Control
- Process Validation
- Failure Analysis
- Vendor Qualification
- R&D

Application Specific Transducers

for the highest quality resolution.

Multiple transducer design for enhanced scan capability.

